IN THE CLAIMS

We claim:

1. A structure comprising:

a first set of features disposed in the scribeline, said first set of features being a subset of product features; and

a second set of features disposed adjacent to said first set of features, said second set occupying a smaller area than said first set, said second set being similar to said first set, said second set being distinguishable from surrounding structures.

- 2. The structure of claim 1 wherein critical dimension (CD) is measured on said first set of features.
- 3. The structure of claim 1 wherein said first set of features and said second set of features differ in spaces between features.
- 4. The structure of claim 1 wherein said first set of features and said second set of features differ in linewidths of features.
- 5. The structure of claim 1 wherein said first set of features and said second set of features have the same pitch for features.

- 6. The structure of claim 1 wherein said first set of features comprises a first array of holes.
- 7. The structure of claim 6 wherein said first array of holes comprises a 5-by-5 square array of holes.
- 8. The structure of claim 6 wherein said second set of features comprises a second array of holes.
- 9. The structure of claim 8 wherein said second array of holes differs from said first array of holes in size of array.
- 10. The structure of claim 8 wherein said second array of holes differs from said first array of holes in space between holes.
- 11. The structure of claim 8 wherein said second array of holes differs from said first array of holes in linewidths of holes.
- 12. A method comprising:

extracting a subset from product features to form a first set of features; extracting a small portion from said first set of features to form a template;

transforming said template into a second set of features by
rotating said template;
scaling spaces between features in said template;
scaling linewidths of features in said template;
merging said first set and said second set of features to form a test structure.

13. The method of claim 12 wherein critical dimension (CD) is measured on said first set of features.

14. A method comprising:

storing a reference image of a test structure, said reference image comprising a first set of features and a second set of features,

said first set of features being a subset of product features, said second set of features disposed adjacent to said first set of features, said second set occupying a smaller area than said first set, said second set being similar to said first set, said second set being distinguishable from surrounding structures;

capturing a test image of a sample, said test image having a plurality of portions;

performing pattern recognition of each of said portions relative to said reference image;

evaluating similarity of each of said portions to said reference image; determining a score for each of said portions; ranking said portions from highest score to lowest score; and determining location on said sample of said portion with highest score.

- 15. The method of claim 14 wherein said score depends on said first set of features and said second set of features.
- 16. The method of claim 14 wherein said first set of features comprises a first array of holes and said second set of features comprises a second array of holes, said second array of holes differing from said first array of holes.